

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of: **Takashi FUJITA et al.**

Art Unit: **1797**

Application Number: **10/561,538**

Examiner: **Xiaoyun Xu**

Filed: **December 19, 2005**

Confirmation Number: **9367**

For: **SPECIFIC COMPONENT MEASURING METHOD BY SPECTRAL
MEASUREMENT**

Attorney Docket Number: **053362**
Customer Number: **38834**

STATEMENT UNDER 37 CFR §1.704(d)

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

June 22, 2010

Sir:

Applicants direct the attention of the Patent and Trademark Office to the documents listed on the attached PTO/SB/08. A copy of each non- U.S. document is attached.

Each listed document was first cited in a communication from a foreign patent office and the communication was not received by any person defined in 37 C.F.R. §1.56(c) more than 30 days before filing of this paper.

If there are any fees due in connection with the filing of this paper, please charge Deposit Account No. 50-2866.

Respectfully submitted,

WESTERMAN, HATTORI, DANIELS & ADRIAN, LLP

/Andrew G. Melick/

Andrew G. Melick
Attorney for Applicants
Registration No. 56,868
Telephone: (202) 822-1100
Facsimile: (202) 822-1111

AGM/lp

Enclosures: PTO/SB/08; Foreign Communication; 2 Documents